

STW #

PATENT Attorney Docket No. 02887.0257-00

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:		
Akira HAMAGUCHI <i>et. al.</i>		) Group Art Unit: 2624
Application No.: 10/687,828		) ) Examiner: Vikkram BALI
Filed:	October 20, 2003	) Confirmation No.: 2967
For:	METHOD AND APPARATUS FOR DETERMINING DEFECT DETECTION SENSITIVITY DATA, CONTROL METHOD OF DEFECT DETECTION APPARATUS, AND METHOD AND APPARATUS FOR DETECTING DEFECT OF SEMICONDUCTOR DEVICES	) ) ) ) )

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

## PETITION FOR EXTENSION OF TIME

Applicants petition for a three month extension of time to file a reply to the Office Action of January 25, 2007. A fee payment of \$1,020.00 is enclosed.

Please grant any additional extensions of time required to enter the attached reply and charge any additional required fees to Deposit Account 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW, GARRETT & DUNNER, L.L.P.

Dated: July 24, 2007

Richard V. Burgujian

Reg. No. 37/74/4007 MAHMED1 00000050 10687828

(202) 408-4000 1253

1020.00 OP